

Form 1449*	Atty. Docket No.: 303.382US2	Serial No. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant: Joseph E. Geusic et al.	
	Filing Date: Herewith	Group: Unknown

U.S. PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WSL	3,968,564	07/13/1976	Springthorpe, A.J.	29	580	04/30/75
	4,920,070	04/24/1990	Mukai, R.	437	173	11/27/87
	4,970,578	11/13/1990	Tong, E.K., et al.	357	81	09/28/88
	5,128,831	07/07/1992	Fox, III, A.C., et al.	361	396	10/31/91
	5,221,633	06/22/1993	Holm, P.M., et al.	437	51	09/09/91
	5,352,998	10/04/1994	Tamino, N.	333	247	10/01/93
	5,362,976	11/08/1994	Suzuki, K.	257	81	10/26/92
	5,409,563	04/25/1995	Cathey	156	643	02/26/93
	5,489,554	02/06/1996	Gates, J.L.	437	208	02/04/94
	5,532,506	07/02/1996	Tserng, H.Q.	257	276	11/14/94
	5,604,835	02/18/1997	Nakamura, T., et al.	385	129	12/22/94
	5,641,545	06/24/1997	Sandhu, G.S.	427	573	06/07/95
	5,656,548	08/12/1997	Zavracky, P.M., et al.	438	23	09/19/95
	5,682,062	10/28/1997	Gaul, S.J.	257	686	06/05/95
	5,729,038	03/17/1998	Young, W.R., et al.	257	460	12/15/95
	5,742,100	04/21/1998	Schroeder, J.A., et al.	257	778	03/27/95
	5,760,478	06/02/1998	Rozso, F.M., et al.	257	777	08/20/96
	5,767,001	06/16/1998	Bertagnolli, E., et al.	438	455	05/22/94
	5,798,297	08/25/1998	Winnerl, J., et al.	438	622	05/02/94
	5,834,849	11/10/1998	Lane, C.F.	257	786	02/13/96
	5,844,289	12/01/1998	Teranishi, N., et al.	257	432	05/21/97
	5,858,814	01/12/1999	Goossen, K.W., et al.	438	107	12/12/96
	5,897,333	04/27/1999	Goossen, K.W., et al.	438	455	03/14/97
	5,900,674	05/04/1999	Wojnarowski, R.J., et al.	257	774	12/23/96
	5,901,050	05/04/1999	Imai, R.	361	820	08/21/97
	5,902,118	05/11/1999	Hubner, H.	438	106	07/03/95
	5,903,045	05/11/1999	Bertin, C.L., et al.	257	621	04/30/96
	5,915,167	06/22/1999	Leedy, G.J.	438	108	04/04/97
	5,952,665	09/14/1999	Bhargava, R.N.	250	483.1	11/28/97

FOREIGN PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
WSL	03-013907	01/22/1991	Japan	G02B	6/12		
	04-263462	09/18/1992	Japan	H01L	25/04		
	05-145060	06/11/1993	Japan	H01L	29/44		
	91/11833	08/08/1991	PCT	H01R	9/00		
	94/05039	03/03/1994	PCT	H01L	23/48		

Examiner

Date Considered

3/14/02

*Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

09/6/18648
07/18/00

Form 1449*	Atty. Docket No.: 303.382US2	Serial No. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant: Joseph E. Geusic et al.	09/6/8, 648
	Filing Date: Herewith	Group: Unknown

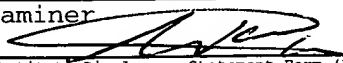
FOREIGN PATENT DOCUMENTS

**Examiner						Translation
n	Indeument Number	Date	Country	Class	Subclass	Yes
No						

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

WSL	Forbes, L., et al., "Resonant Forward-Biased Guard-Ring Diodes for Suppression of Substrate Noise in Mixed-Mode CMOS Circuits", <u>Electronics Letters</u> , 31, 720-721, (April 1995)
	Foster, R., et al., "High Rate Low-Temperature Selective Tungsten", In: <u>Tungsten and Other Refractory Metals for VLSI Applications III</u> , V.A. Wells, ed., Materials Res. Soc., Pittsburgh, PA, 69-72, (1988)
	Gong, S., et al., "Techniques for Reducing Switching Noise in High Speed Digital Systems", <u>Proceedings of the 8th Annual IEEE International ASIC Conference and Exhibit</u> , Austin, TX, 21-24, (1995)
	Heavens, O., <u>Optical Properties of Thin Solid Films</u> , Dover Pubs. Inc., New York, 155-206, (1965)
	Horie, H., et al., "Novel High Aspect Ratio Aluminum Plug for Logic/DRAM LSI's Using Polysilicon-Aluminum Substitute", <u>Technical Digest: IEEE International Electron Devices Meeting</u> , San Francisco, CA, 946-948, (1996)
	Kim, Y.S., et al., "A Study on Pyrolysis DMEAA for Selective Deposition of Aluminum", In: <u>Advanced Metallization and Interconnect Systems for ULSI Applications in 1995</u> , R.C. Ellwanger, et al., (eds.), Materials Research Society, Pittsburgh, PA, 675-680, (1996)
	Klaus, et al., "Atomic Layer Controlled Growth of SiO ₂ Films Using Binary Reaction Sequence Chemistry", <u>Applied Physics Lett.</u> 70(9), 1092-94, (3 March 1997)
	Lehmann, et al., "A Novel Capacitor Technology Based on Porous Silicon", <u>Thin Solid Films</u> 276, Elsevier Science, 138-42, (1996)
	Lehmann, V., "The Physics of Macropore Formation in Low Doped n-Type Silicon", <u>Journal of the Electrochemical Society</u> , 140(10), 2836-2843, (Oct. 1993)
V	Masu, K., et al., "Multilevel Metallization Based on Al CVD", <u>1996 IEEE Symposium on VLSI Technology, Digest of Technical Papers</u> , Honolulu, HI, 44-45, (June 11-13, 1996)

Examiner 	Date Considered 3/14/02
--	----------------------------

*Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form 1449*	Atty. Docket No.: 303.382US2	Serial No. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant: Joseph E. Geusic et al.	09/16/88, 648
	Filing Date: Herewith	Group: Unknown

OTHER DOCUMENTS

**Examiner
Initial

(Including Author, Title, Date, Pertinent Pages, Etc.)

WSL	McCredie, B.D., et al., "Modeling, Measurement, and Simulation of Simultaneous Switching Noise", <u>IEEE Transactions on Components, Packaging, and Manufacturing Technology -- Part B</u> , 19, 461-472, (Aug. 1996)
	Muller, K., et al., "Trench Storage Node Technology for Gigabit DRAM Generations", <u>Digest IEEE International Electron Devices Meeting</u> , San Francisco, CA, 507-510, (Dec. 1996)
	Ohba, T., et al., "Evaluation on Selective Deposition of CVD W Films by Measurement of Surface Temperature", <u>In: Tungsten and Other Refractory Metals for VLSI Applications II</u> , Materials Research Society, Pittsburgh, PA, 59-66, (1987)
	Ohba, T., et al., "Selective Chemical Vapor Deposition of Tungsten Using Silane and Polysilane Reductions", <u>In: Tungsten and Other Refractory Metals for VLSI Applications IV</u> , Materials Research Society, Pittsburgh, PA, 17-25, (1989)
	Ott, A.W., et al., "Al3O3 Thin Film Growth on Si(100) Using Binary Reaction Sequence Chemistry", <u>Thin Solid Films</u> , Vol. 292, 135-44, (1997)
	Ramo, S., et al., <u>Fields and Waves in Communication Electronics, Third Edition</u> , John Wiley & Sons, Inc., pp. 428-433, (1994)
	Senthinathan, R., et al., "Reference Plane Parasitics Modeling and Their Contribution to the Power and Ground Path "Effective" Inductance as Seen by the Output Drivers", <u>IEEE Transactions on Microwave Theory and Techniques</u> , 42, 1765-1773, (Sep. 1994)
	Stanisic, B.R., et al., "Addressing Noise Decoupling in Mixed-Signal IC's: Power Distribution Design and Cell Customization", <u>IEEE Journal of Solid-State Circuits</u> , 30, 321-326, (Mar. 1995)
	Suntola, T., "Atomic Layer Epitaxy", <u>Handbook of Crystal Growth 3, Thin Films of Epitaxy, Part B: Growth Mechanics and Dynamics</u> , Elsevier, Amsterdam, 601-63, (1994)
	Sze, S.M., <u>VLSI Technology</u> , 2nd Edition, Mc Graw-Hill, NY, 90, (1988)
	Vittal, A., et al., "Clock Skew Optimization for Ground Bounce Control", <u>1996 IEEE/ACM International Conference on Computer-Aided Design, Digest of Technical Papers</u> , San Jose, CA, 395-399, (Nov. 10-14, 1996)

Examiner

Date Considered

*Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

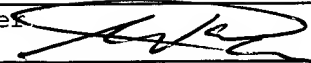
Form 1449*	Atty. Docket No.: 303.382US2	Serial No. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant: Joseph E. Geusic et al.	09/6/8, 648
	Filing Date: Herewith	Group: Unknown

OTHER DOCUMENTS

**Examiner
Initial

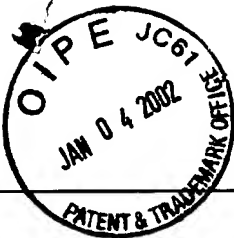
(Including Author, Title, Date, Pertinent Pages, Etc.)

WSE | Wooley, et al., "Experimental Results and Modeling Techniques for Substrate Noise in Mixed Signal Integrated Circuits", IEEE Journal of Solid State Circuits, Vol SC-28, 420-30, (1993)

Examiner 	Date Considered 3/14/02
--	-------------------------

*Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Sheet 1 of 1

Form 1449*

Atty. Docket No.: 303.382US2

Serial No. 09/618,648

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT
(Use several sheets if necessary)

Applicant: Joseph E. Geusic et al.

Filing Date: July 18, 2000

Group: 2814

U.S. PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
						If Appropriate
WSL	5,416,872	05/16/1995	Sizer, II, T., et al.	385	92	07/06/93
↓	6,150,188	11/21/2000	Geusic, J.E., et al.	438	31	02/26/98
↓	6,181,864	01/30/2001	Jang, W., et al.	385	137	08/13/98
↓	6,198,168	03/06/2001	Geusic, J.E., et al.	257	774	01/20/98

FOREIGN PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
						Yes No

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

**Examiner
Initial

3/14/02

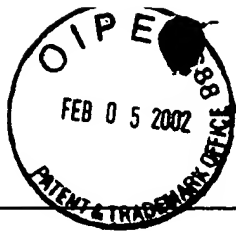
Examiner

Date Considered

3/14/02

Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Sheet 1 of 1

Form 1449*

Atty. Docket No.: 303.382US2

Serial No. 09/618,648

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT
(Use several sheets if necessary)

Applicant: Joseph E. Geusic et al.

Filing Date: July 18, 2000

Group: 2814

U.S. PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<u>WSL</u>	5,587,119	12/24/1996	White, D.M.	264	104	05/26/95
<u> </u>	5,858,877	01/12/1999	Dennison, C.H., et al.	438	700	01/21/97
<u> </u>	5,963,088	10/05/1999	Czarnul, Z., et al.	330	69	07/29/97
<u> </u>	6,122,187	09/19/2001	Ahn, K.Y., et al.	365	63	11/23/98
<u> </u>	6,143,616	11/07/2000	Geusic, J.E., et al.	438	389	08/22/97
<u> </u>	6,187,677	02/13/2001	Ahn, K.Y.	438	667	08/22/97
<u> </u>	6,281,042	08/28/2001	Ahn, K.Y., et al.	438	108	08/31/98

FOREIGN PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes <input type="checkbox"/> No <input type="checkbox"/>
	56-055067	05/15/1981	Japan	H01L	23/52	

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

**Examiner
Initial

Examiner

Date Considered

*Substitute Disclosure Statement Form (PTO-1449)

**EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.